

LL014-VB Datasheet N-Channel 60-V (D-S) MOSFET

PRODUC	CT SUMMARY		
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^a	Q _g (Typ.)
<u></u>	0.076 at V _{GS} = 10 V	4.5	10 nC
60	0.085 at V _{GS} = 4.5 V	3.5	TOTIC

FEATURES

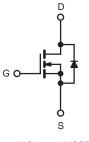
- · Halogen-free
- Trench Power MOSFET

APPLICATIONS

· Load Switches for Portable Devices







N-Channel MOSFET

Parameter		Symbol	Limit	Unit
Drain-Source Voltage		V _{DS}	60	V
Gate-Source Voltage		V _{GS}	± 20	V
	T _C = 25 °C		4.5	
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C	I _D	3.2 ^a	
	T _A = 25 °C	О	2.7	
	T _A = 70 °C		2.3	A
Pulsed Drain Current	-	I _{DM}	20	
Continuous Source-Drain Diode Current	T _C = 25 °C	I _S	3.2	
Continuous Cource Drain Diode Current	T _A = 25 °C	'5	2.1 ^{b, c}	
	T _C = 25 °C		4.0	
Maximum Power Dissipation	T _C = 70 °C	P _D	3.0	w
	T _A = 25 °C	טי	2.5 ^{b, c}	vv
	T _A = 70 °C		1.6 ^{b, c}	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	°C
Soldering Recommendations (Peak Temper	ature) ^{e, f}		260	- C

THERMAL RESISTANCE BATINGS

ITTERMAL RESISTANCE RA	mas					
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{a, c, d}	t ≤ 5 s	R _{thJA}	40	50	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	R _{thJF}	15	20	0/11	

Notes:

a. Package limited, T_C = 25 °C.
b. Surface Mounted on 1" x 1" FR4 board.

c. t = 10 s.

d. Maximum under Steady State conditions is 95 °C/W.

e. See Reliability Manual for profile. The ChipFET is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.

f. Rework Conditions: manual soldering with a soldering iron is not recommended for leadless components.

SPECIFICATIONS $T_J = 25 \ ^{\circ}C$,	unless othe	erwise noted				
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 V, I_{D} = 250 \mu A$	60			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		25		
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	10 - 200 μΛ		- 4.0		mV/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \ \mu A$	1.0		2.5	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 12 V$			± 100	nA
	1	$V_{DS} = 60 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			1	
Zero Gate Voltage Drain Current	IDSS	V _{DS} = 60 V, V _{GS} = 0 V, T _J = 55 °C			10	μA
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5$ V, V_{GS} = 4.5 V	30			Α
	Р	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 4.0 \text{ A}$		0.076		Ω
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 V, I_{D} = 3.0 A$		0.085		
Forward Transconductance ^a	9 _{fs}	V _{DS} = 10 V, I _D = 4.0 A		45		S
Dynamic ^b			1			
Input Capacitance	C _{iss}			810		
Output Capacitance	C _{oss}	$V_{DS} = 30V^{,} V_{GS} = 0 V, f = 1 MHz$		120		pF
Reverse Transfer Capacitance	C _{rss}			100		
7,10,10	0	$V_{DS} = 30 \text{ V}, \text{ V}_{GS} = 10 \text{ V}, \text{ I}_{D} = 4.0 \text{ A}$		22	33	
Total Gate Charge	Qg			10	15	nC
Gate-Source Charge	Q _{gs}	V_{DS} = 30 V, V_{GS} = 4.5 V, I_{D} = 3.0 A		2.5		
Gate-Drain Charge	Q _{gd}			1.7		
Gate Resistance	Rg	f = 1 MHz		2.4		Ω
Turn-on Delay Time	t _{d(on)}			15	25	
Rise Time	tr	V_{DD} =30V, , R_{L} = 1.5 Ω		10	15	
Turn-Off Delay Time	t _{d(off)}	$\text{I}_\text{D}\cong$ 4.0 A, V_GEN = 4.5 V, R_g = 1 Ω		35	55	- ns -
Fall Time	t _f			12	20	
Turn-on Delay Time	t _{d(on)}			10	15	
Rise Time	t _r	V_{DD} = 30V , R_{L} = 1.5 Ω		12	20	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 4.0 \text{ A}, \text{ V}_{\text{GEN}} = 10 \text{ V}, \text{ R}_{\text{g}} = 1 \Omega$		25	40	
Fall Time	t _f			10	15	
Drain-Source Body Diode Characteristi	cs		1			
Continuous Source-Drain Diode Current	ا _S	T _C = 25 °C			7.2	
Pulse Diode Forward Current	I _{SM}				30	A
Body Diode Voltage	V _{SD}	I _S = 4.0 A, V _{GS} = 0 V		0.8	1.2	V
Body Diode Reverse Recovery Time	t _{rr}			20	40	ns
Body Diode Reverse Recovery Charge	Q _{rr}			10	20	nC
Reverse Recovery Fall Time	t _a	$I_F = 4.0 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, \text{ T}_J = 25 ^\circ\text{C}$		10		ns
Reverse Recovery Rise Time	t _b			10		

Notes:

a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %

b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

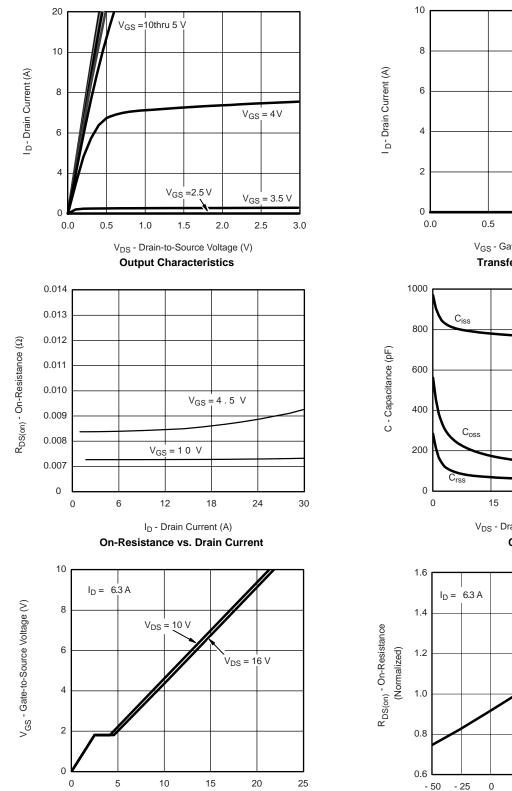
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T_C = - 55

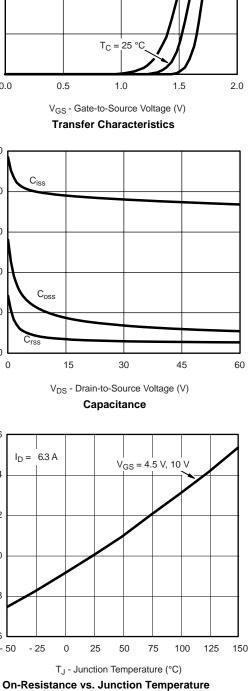
T_C = 125 °C

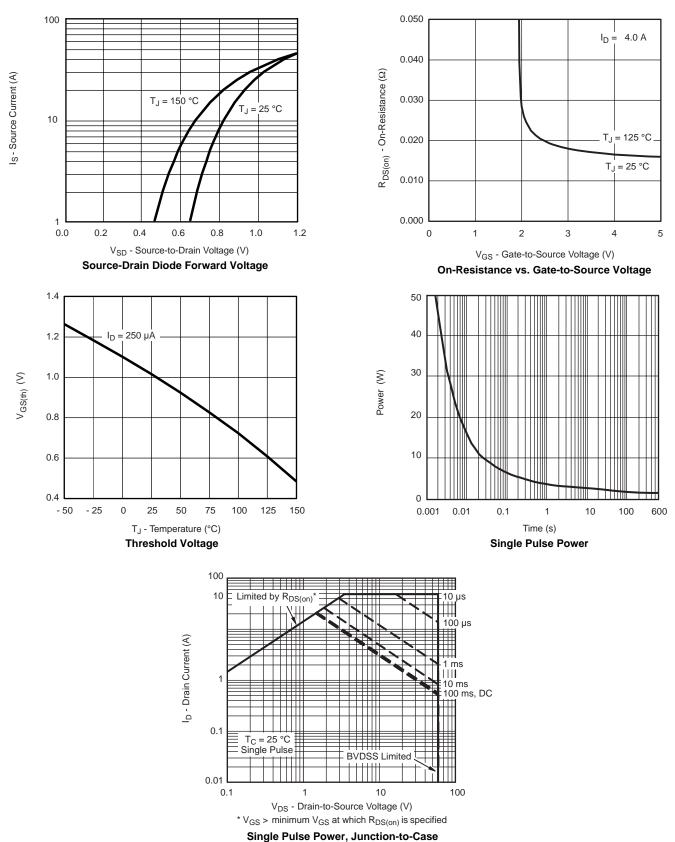


TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

Qg - Total Gate Charge (nC)

Gate Charge



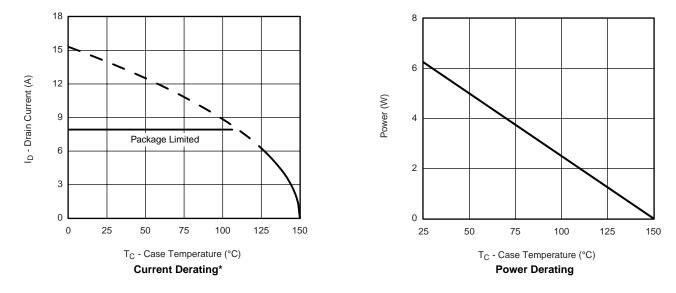


TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

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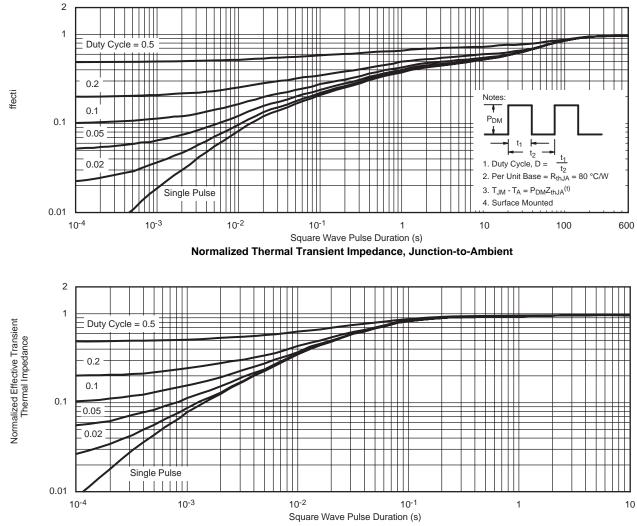




TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

* The power dissipation P_D is based on $T_{J(max)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



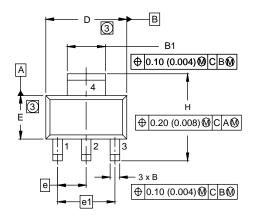


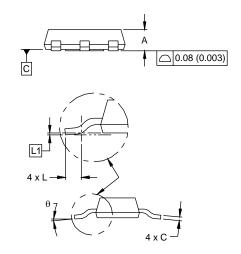
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

Normalized Thermal Transient Impedance, Junction-to-Foot



SOT-223 (HIGH VOLTAGE)





DIM.	MILLIMETERS		INCHES		
	MIN.	MAX.	MIN.	MAX.	
А	1.55	1.80	0.061	0.071	
В	0.65	0.85	0.026	0.033	
B1	2.95	3.15	0.116	0.124	
С	0.25	0.35	0.010	0.014	
D	6.30	6.70	0.248	0.264	
E	3.30	3.70	0.130	0.146	
е	2.30 BSC		0.0905 BSC		
e1	4.60 BSC		0.181 BSC		
Н	6.71	7.29	0.264	0.287	
L	0.91	-	0.036	-	
L1	0.061 BSC		0.002	4 BSC	
θ	-	10'	-	10'	

Notes

1. Dimensioning and tolerancing per ASME Y14.5M-1994.

2. Dimensions are shown in millimeters (inches).

3. Dimension do not include mold flash.

4. Outline conforms to JEDEC outline TO-261AA.



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